

## INFORMATION DISCLOSURE CITATION

Atty. Docket No. 03180.0357	Application TBA No. 10801992
Applicant Hiroshi MATSUSHITA et al.	
Filing Date March 17, 2004	Group 2812 TBA Andre Steiner

## U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
<del>AS</del>	<del>2001-210097</del>	<del>08/03/2001</del>	<del>Japan</del>	<del>AS</del>	<del>AS</del>	<del>Abstract</del>
<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>
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## FOREIGN PATENT DOCUMENTS

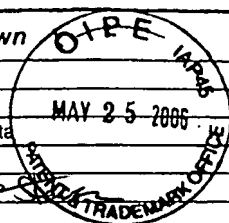
Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No
<del>AS</del>	<del>2001-210097</del>	<del>08/03/2001</del>	<del>Japan</del>	<del>AS</del>	<del>AS</del>
<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>
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<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>	<del>AS</del>

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<del>AS</del>	Copy of U.S. Patent Application for Hiroshi MATSUSHITA et al., Serial No. 10/107,297, filed March 28, 2002
<del>AS</del>	Copy of U.S. Patent Application for Hiroshi MATSUSHITA, Serial No. 10/608,155, filed June 30, 2003
<del>AS</del>	K. Mitsutake, et al., "New Method of Extraction of Systematic Failure Component", Proc. 10 <sup>th</sup> Int. Symp. Semiconductor Manufacturing, pp. 247-250, (2001)
<del>AS</del>	M. Sugimoto et al., "Characterization Algorithm of Failure Distribution for LSI Yield Improvement", Proc. 10 <sup>th</sup> Int. Symp. Semiconductor Manufacturing, pp. 275-278, (2001)
<del>AS</del>	K. Nakamae, et al., "Fail Pattern Classification and Analysis System of Memory Fail Bit Maps", Proc. 4 <sup>th</sup> Int. Conf. Modeling and Simulation of Microsystems, pp. 598-601, (2001)

Examiner Andre Steiner	Date Considered 10/21/07
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (Use as many sheets as necessary)			Application Number	10/801,992	
			Filing Date	March 17, 2004	
			First Named Inventor	Hiroshi Matsushita	
			Art Unit	2184 28/2	
			Examiner Name	Unknown	
Sheet	1	of	1	Attorney Docket Number	3180.0357



U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. <sup>1</sup>	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
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FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
/	/	JP 2002-269109	9/20/02	Hitachi Ltd.	/	Abstract
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NON PATENT LITERATURE DOCUMENTS			
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/	/	Notification of Reason for Refusal issued by the Japanese Patent Office, dispatched on May 9, 2006, for Japanese Patent Application No. 2003-076411, and English-language translation thereof	/
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